


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/711,772	CHARYTAN ET AL.	
	Examiner	Art Unit	
	/BINH K. TIEU/	2614	

SEARCHED			
Class	Subclass	Date	Examiner
379	111	12/14/2007	BKT
↓	114.01	↓	↓
	114.15		
	114.17		
	114.2		
	91.01		
↓	93.02-04	↓	↓
235	380, 487		
	490-492	↓	↓

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
WEST DATABASES SEARCH	12/6/2007	BKT
WEST DATABASES SEARCH	12/10/2007	BKT
WEST DATABASES SEARCH	12/11/2007	BKT